

Date Created : 2009/05/06
Date Issued On : 2009/10/23
PCN# : Q2091901

DESIGN/PROCESS CHANGE NOTIFICATION -- FINAL

This is to inform you that a design and/or process change will be made to the following product(s). This notification is for your information and concurrence.

If you require data or samples to qualify this change, please contact **Fairchild Semiconductor within 30 days of receipt of this notification.**

Updated process quality documentation, such as FMEAs and Control Plans, are available for viewing upon request.

If you have any questions concerning this change, please contact:

Technical Contact:

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PCN Originator:

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Implementation of change:

Expected 1st Device Shipment Date: 2010/01/16

Earliest Year/Work Week of Changed Product: D0952

Change Type Description: Mold Compound

Description of Change (From): Products assembled in the SC70 package using the currently qualified mold compounds shown below.

Description of Change (To): Products assembled in the SC70 package using the new alternative mold compounds shown below.

Reason for Change : This is a change to the mold compounds used for Fairchild products assembled in SC70 package. The qualified alternative mold compounds are low halogen materials with improved thermal-mechanical properties. There are no changes to the currently approved assembly facilities or any other materials used to produce these products. Package outline drawings of the affected products remain un-changed. Affected products will be fully compliant to all published data sheet specifications. Quality and reliability will remain at the highest standards already demonstrated with Fairchild's existing SC70 products. Please do not delay in requesting any samples required to approve of this change as there is a potential for a mold compound material shortage if this PCN is not approved within the timeframe noted above. Please contact your local Fairchild Sales representative to place orders for a sufficient volume of product if your approval process will require more than 90 days.

Qual/REL Plan Numbers : Q20090383; Q20090510

Qualification :

The qualification of the Mold Compound for SC70 passed the qualification requirements as defined in the corresponding iRel QP#.

Change To

	Assembly Location		
	Fairchild-Cebu	HANA	JCET
Change From These Mold Compounds	COOKSON AMC-2RC	NITTO MP8000AN	ELL-2K1
Change To Include These Alternative Mold Compounds	COOKSON CK5000A HENKEL GR828HS	SUMITOMO G600	GE1030S

Results/Discussion for Qual Plan Number Q20090383

Test: (Autoclave) Conditions: 100%RH, 121C Standard: JESD22-A102					
Lot	Device	96-HOURS		Failure Code	
Q20090383AAACLV	NC7SZ125M5X	0/77			
Q20090383BAACLV	NC7SB3157P6X	0/77			
Q20090383CAACLV	NC7SZ125P5X	0/77			
Q20090383DAACLV	FHP3131IS6X	0/77			
Q20090383EAACLV	FSA66M5X	0/77			

Test: (Gate Leakage Negative) Conditions: 155C, -400V Standard: AEC-Q100-006			
Lot	Device	Results	Failure Code
Q20090383AAGATE-	NC7SZ125M5X	0/3	
Q20090383BAGATE-	NC7SB3157P6X	0/3	
Q20090383CAGATE-	NC7SZ125P5X	0/3	
Q20090383DAGATE-	FHP3131IS6X	0/3	
Q20090383EAGATE-	FSA66M5X	0/3	

Test: (Gate Leakage Positive) Conditions: 155C, 400V Standard: AEC-Q100-006			
Lot	Device	Results	Failure Code
Q20090383AAGATE+	NC7SZ125M5X	0/3	
Q20090383BAGATE+	NC7SB3157P6X	0/3	
Q20090383CAGATE+	NC7SZ125P5X	0/3	
Q20090383DAGATE+	FHP3131IS6X	0/3	
Q20090383EAGATE+	FSA66M5X	0/3	

Test: (High Temperature Storage Life) Conditions: 150C Standard: JESD22-A103					
Lot	Device	168-HOURS	500-HOURS	1000-HOURS	Failure Code
Q20090383AAHTSL	NC7SZ125M5X	0/77			
			0/77		
				0/77	
Q20090383BAHTSL	NC7SB3157P6X	0/77			
			0/77		
				0/77	
Q20090383CAHTSL	NC7SZ125P5X	0/77			
			0/77		
				0/77	
Q20090383DAHTSL	FHP3131IS6X	0/77			
			0/77		
				0/77	
Q20090383EAHTSL	FSA66M5X	0/77			
			0/77		
				0/77	

Test: (Highly Accelerated Stress Test) Conditions: 85%RH, 110C, TBDV Standard: JESD22-A110			
Lot	Device	264-HOURS	Failure Code
Q20090383AAHAST2	NC7SZ125M5X	0/45	
Q20090383BAHAST2	NC7SB3157P6X	0/45	
Q20090383CAHAST2	NC7SZ125P5X	0/45	
Q20090383DAHAST2	FHP3131IS6X	0/45	
Q20090383EAHAST2	FSA66M5X	0/45	

Test: (Lead Integrity) Conditions: Standard: JESD22-B105			
Lot	Device	Results	Failure Code
Q20090383AALINTB	NC7SZ125M5X	0/5	
Q20090383BALINTB	NC7SB3157P6X	0/5	

Q20090383CALINTB	NC7SZ125P5X	0/5			
Q20090383DALINTB	FHP3131S6X	0/5			
Q20090383EALINTB	FSA66M5X	0/5			
Test: (Moisture Sensitivity) Conditions: Standard: J-STD_020					
Lot	Device	Results	Failure Code		
Q20090383AAMSLNL1A	NC7SZ125M5X	0/11			
Q20090383BAMSLNL1A	NC7SB3157P6X	0/11			
Q20090383CAMSLNL1A	NC7SZ125P5X	0/11			
Q20090383DAMSLNL1A	FHP3131S6X	0/11			
Q20090383EAMSLNL1A	FSA66M5X	0/11			
Test: (Physical Dimensions) Conditions: Standard: JESD22-B100					
Lot	Device	Results	Failure Code		
Q20090383AAPHYD	NC7SZ125M5X	0/5			
Q20090383BAPHYD	NC7SB3157P6X	0/5			
Q20090383CAPHYD	NC7SZ125P5X	0/5			
Q20090383DAPHYD	FHP3131S6X	0/5			
Q20090383EAPHYD	FSA66M5X	0/5			
Test: (Precondition) Conditions: Standard: JESD22-A113					
Lot	Device	Results	Failure Code		
Q20090383AAPCNL1A	NC7SZ125M5X	0/353			
Q20090383BAPCNL1A	NC7SB3157P6X	0/353			
Q20090383CAPCNL1A	NC7SZ125P5X	0/353			
Q20090383DAPCNL1A	FHP3131S6X	0/353			
Q20090383EAPCNL1A	FSA66M5X	0/353			
Test: (Solderability) Conditions: Standard: JESD22-B102					
Lot	Device	Results	Failure Code		
Q20090383AASOLDCA	NC7SZ125M5X	0/11			
Q20090383AASOLDCB	NC7SZ125M5X	0/11			
Q20090383BASOLDCA	NC7SB3157P6X	0/11			
Q20090383BASOLDCB	NC7SB3157P6X	0/11			
Q20090383CASOLDCA	NC7SZ125P5X	0/11			
Q20090383CASOLDCB	NC7SZ125P5X	0/11			
Q20090383DASOLDCA	FHP3131S6X	0/11			
Q20090383DASOLDCB	FHP3131S6X	0/11			
Q20090383EASOLDCA	FSA66M5X	0/11			
Q20090383EASOLDCB	FSA66M5X	0/11			
Test: (Static Op Life) Conditions: 150C, TBDV Standard: JESD22-A108					
Lot	Device	168-HOURS	500-HOURS	1000-HOURS	Failure Code
Q20090383AASOPL1	NC7SZ125M5X	0/77			
			0/77		
Q20090383BASOPL1	NC7SB3157P6X	0/77		0/77	
			0/77		
				0/77	
Q20090383CASOPL1	NC7SZ125P5X	0/77			
			0/77		
				0/77	
Q20090383DASOPL1	FHP3131S6X	0/77			
			0/77		
				0/77	
Q20090383EASOPL1	FSA66M5X	0/77			
			0/77		
				0/77	
Test: (Temperature Cycle) Conditions: -65C, 150C Standard: JESD22-A104					
Lot	Device	100-CYCLES	500-CYCLES	Failure Code	
Q20090383AATMCL1	NC7SZ125M5X	0/77			
Q20090383AATMCL1	NC7SZ125M5X		0/77		
Q20090383BATMCL1	NC7SB3157P6X	0/77			
Q20090383BATMCL1	NC7SB3157P6X		0/77		
Q20090383CATMCL1	NC7SZ125P5X	0/77			
Q20090383CATMCL1	NC7SZ125P5X		0/77		
Q20090383DATMCL1	FHP3131S6X	0/77			
Q20090383DATMCL1	FHP3131S6X		0/77		
Q20090383EATMCL1	FSA66M5X	0/77			
Q20090383EATMCL1	FSA66M5X		0/77		

Results/Discussion for Qual Plan Number Q20090510

Test: (Autoclave) Conditions: 100%RH, 121C Standard: JESD22-A102					
Lot	Device	96-HOURS	Failure Code		
Q20090510AAACL	FDG901D	0/77			
Q20090510ABACL	FDG901D	0/77			
Q20090510ACACL	FDG901D	0/77			
Q20090510BAACL	FDG313N	0/77			
Q20090510BACL	FDG313N	0/77			
Q20090510BCACL	FDG313N	0/77			
Q20090510BDACL	FDG313N	0/77			
Q20090510CAACL	FDG6323L	0/77			
Q20090510CBACL	FDG6323L	0/77			
Q20090510CCACL	FDG6323L	0/77			
Q20090510CDAACL	FDG6323L	0/77			
Q20090510CEACL	FDG6323L	0/77			
Q20090510DAACL	NC7WZ17P6X	0/77			
Q20090510DBACL	NC7WZ17P6X	0/77			
Q20090510EAACL	FDG361N	0/77			
Q20090510EBACL	FDG361N	0/77			
Test: (Gate Leakage Negative) Conditions: 155C, -400V Standard: AEC-Q100-006					
Lot	Device	Results	Failure Code		
Q20090510AAGATE-	FDG901D	0/3			
Q20090510ABGATE-	FDG901D	0/3			
Q20090510ACGATE-	FDG901D	0/3			
Q20090510BAGATE-	FDG313N	0/3			
Q20090510BBGATE-	FDG313N	0/3			
Q20090510BCGATE-	FDG313N	0/3			
Q20090510BDGATE-	FDG313N	0/3			
Q20090510CAGATE-	FDG6323L	0/3			
Q20090510CBGATE-	FDG6323L	0/3			
Q20090510CCGATE-	FDG6323L	0/3			
Q20090510CDGATE-	FDG6323L	0/3			
Q20090510CEGATE-	FDG6323L	0/3			
Q20090510DAGATE-	NC7WZ17P6X	0/3			
Q20090510DBGATE-	NC7WZ17P6X	0/3			
Q20090510EAGATE-	FDG361N	0/3			
Q20090510EBGATE-	FDG361N	0/3			
Test: (Gate Leakage Positive) Conditions: 155C, 400V Standard: AEC-Q100-006					
Lot	Device	Results	Failure Code		
Q20090510AAGATE+	FDG901D	0/3			
Q20090510ABGATE+	FDG901D	0/3			
Q20090510ACGATE+	FDG901D	0/3			
Q20090510BAGATE+	FDG313N	0/3			
Q20090510BBGATE+	FDG313N	0/3			
Q20090510BCGATE+	FDG313N	0/3			
Q20090510BDGATE+	FDG313N	0/3			
Q20090510CAGATE+	FDG6323L	0/3			
Q20090510CBGATE+	FDG6323L	0/3			
Q20090510CCGATE+	FDG6323L	0/3			
Q20090510CDGATE+	FDG6323L	0/3			
Q20090510CEGATE+	FDG6323L	0/3			
Q20090510DAGATE+	NC7WZ17P6X	0/3			
Q20090510DBGATE+	NC7WZ17P6X	0/3			
Q20090510EAGATE+	FDG361N	0/3			
Q20090510EBGATE+	FDG361N	0/3			
Test: (High Humidity, High Temp, Rev. Bias) Conditions: 85%RH, 85C, 20V Standard: JESD22-A101B					
Lot	Device	168-HOURS	500-HOURS	1000-HOURS	Failure Code
Q20090510BAH3TRB	FDG313N	0/77			
			0/77		
				0/77	
Q20090510BBH3TRB		0/77			
			0/77		
				0/77	
Q20090510BCH3TRB		0/77			
			0/77		

				0/77	
Q20090510BDH3TRB		0/77			
			0/77		
				0/77	
Test: (High Temperature Gate Bias) Conditions: 150C, 8V Standard: JESD22-A108					
Lot	Device	168-HOURS	500-HOURS	1000-HOURS	Failure Code
Q20090510BAHTGB		0/77			
			0/77		
				0/77	
Q20090510BBHTGB		0/77			
			0/77		
				0/77	
Q20090510BCHTGB		0/77			
			0/77		
				0/77	
Q20090510BDHTGB		0/77			
			0/77		
				0/77	
Test: (High Temperature Reverse Bias) Conditions: 150C, 20V Standard: JESD22-A108					
Lot	Device	168-HOURS	500-HOURS	1000-HOURS	Failure Code
Q20090510BAHTRB		0/77			
			0/77		
				0/77	
Q20090510BBHTRB		0/77			
			0/77		
				0/77	
Q20090510BCHTRB		0/77			
			0/77		
				0/77	
Q20090510BDHTRB		0/77			
			0/77		
				0/77	
Test: (Highly Accelerated Stress Test) Conditions: 85%RH, 110C, 24V Standard: JESD22-A110					
Lot	Device	132-HOURS	264-HOURS		Failure Code
Q20090510EAHAST2	FDG361N	0/77			
Q20090510EAHAST2	FDG361N		0/77		
Q20090510EBHAST2	FDG361N	0/77			
Q20090510EBHAST2	FDG361N		0/77		
Test: (Highly Accelerated Stress Test) Conditions: 85%RH, 110C, 5V Standard: JESD22-A110					
Lot	Device	132-HOURS	264-HOURS		Failure Code
Q20090510AAHAST2	FDG901D	0/77			
Q20090510AAHAST2	FDG901D		0/77		
Q20090510ABHAST2	FDG901D	0/77			
Q20090510ABHAST2	FDG901D		0/77		
Q20090510ACHAST2	FDG901D	0/77			
Q20090510ACHAST2	FDG901D		0/77		
Q20090510DAHAST2	NC7WZ17P6X	0/77			
Q20090510DAHAST2	NC7WZ17P6X		0/77		
Q20090510DBHAST2	NC7WZ17P6X	0/77			
Q20090510DBHAST2	NC7WZ17P6X		0/77		
Test: (Highly Accelerated Stress Test) Conditions: 85%RH, 130C, 20V Standard: JESD22-A110					
Lot	Device	96-HOURS			Failure Code
Q20090510BAHAST1	FDG313N	0/77			
Q20090510BBHAST1	FDG313N	0/77			
Q20090510BCHAST1	FDG313N	0/77			
Q20090510BDHAST1	FDG313N	0/77			
Test: (Power Cycle) Conditions: Delta 100C, 2 Min cycle Standard: MIL-STD-750-1036					
Lot	Device	5000-CYCLES	10000-CYCLES		Failure Code
Q20090510BAPRCL	FDG313N	0/77			
Q20090510BAPRCL	FDG313N		0/77		
Q20090510BBPRCL	FDG313N	0/77			
Q20090510BBPRCL	FDG313N		0/77		
Q20090510BCPRCL	FDG313N	0/77			
Q20090510BCPRCL	FDG313N		0/77		
Q20090510BDPRCL	FDG313N	0/77			

Q20090510BDPRCL	FDG313N		0/77		
Test: (Precondition) Conditions: Standard: JESD22-A113					
Lot	Device	Results		Failure Code	
Q20090510AAPCNL1A	FDG901D	0/231			
Q20090510ABPCNL1A	FDG901D	0/231			
Q20090510ACPCNL1A	FDG901D	0/231			
Q20090510BAPCNL1A	FDG313N	0/308			
Q20090510BBPCNL1A	FDG313N	0/308			
Q20090510BCPCNL1A	FDG313N	0/308			
Q20090510BDPCNL1A	FDG313N	0/308			
Q20090510CAPCNL1A	FDG6323L	0/154			
Q20090510CBPCNL1A	FDG6323L	0/154			
Q20090510CCPCNL1A	FDG6323L	0/154			
Q20090510CDPCNL1A	FDG6323L	0/154			
Q20090510CEPCNL1A	FDG6323L	0/154			
Q20090510DAPCNL1A	NC7WZ17P6X	0/231			
Q20090510DBPCNL1A	NC7WZ17P6X	0/231			
Q20090510EAPCNL1A	FDG361N	0/308			
Q20090510EBPCNL1A	FDG361N	0/308			
Test: (Resistance to Solder Heat) Conditions: Standard: JESD22-B106					
Lot	Device	Results		Failure Code	
Q20090510AARSDH	FDG901D	0/30			
Q20090510ABRSDH	FDG901D	0/30			
Q20090510ACRSDH	FDG901D	0/30			
Q20090510BARSDH	FDG313N	0/30			
Q20090510BBRSDH	FDG313N	0/30			
Q20090510BCRSDH	FDG313N	0/30			
Q20090510BDRSDH	FDG313N	0/30			
Q20090510CARSDH	FDG6323L	0/30			
Q20090510CBRSDH	FDG6323L	0/30			
Q20090510CCRSDH	FDG6323L	0/30			
Q20090510CDRSDH	FDG6323L	0/30			
Q20090510CERSDH	FDG6323L	0/30			
Q20090510DARSDH	NC7WZ17P6X	0/30			
Q20090510DBRSDH	NC7WZ17P6X	0/30			
Q20090510EARSDH	FDG361N	0/30			
Q20090510EBRSDH	FDG361N	0/30			
Test: (Static Op Life) Conditions: 150C, 10V Standard: JESD22-A108					
Lot	Device	168-HOURS	500-HOURS	1000-HOURS	Failure Code
Q20090510EASOPL1	FDG361N	0/77			
			0/77		
				0/77	
Q20090510EBSOPL1		0/77			
			0/77		
				0/77	
Test: (Static Op Life) Conditions: 150C, 5V Standard: JESD22-A108					
Lot	Device	168-HOURS	500-HOURS	1000-HOURS	Failure Code
Q20090510AASOPL1	FDG901D	0/77			
			0/77		
				0/77	
Q20090510ABSOPL1		0/77			
			0/77		
				0/77	
Q20090510ACSOPL1		0/77			
			0/77		
				0/77	
Q20090510DASOPL1	NC7WZ17P6X	0/77			
			0/77		
				0/77	
Q20090510DBSOPL1		0/77			
			0/77		
				0/77	
Test: (TMCL Precon) Conditions: -65CC, 150CC Standard:					
Lot	Device	100-CYCLES	500	Failure Code	
Q20090510AATMCLPC1	FDG901D	0/77			
Q20090510AATMCLPC1	FDG901D		0/77		

Q20090510ABTMCLPC1	FDG901D	0/77		
Q20090510ABTMCLPC1	FDG901D		0/77	
Q20090510ACTMCLPC1	FDG901D	0/77		
Q20090510ACTMCLPC1	FDG901D		0/77	
Test: (Temperature Cycle) Conditions: -65C, 150C Standard: JESD22-A104				
Lot	Device	100-CYCLES	500-CYCLES	Failure Code
Q20090510BATMCL1	FDG313N	0/77		
Q20090510BATMCL1	FDG313N		0/77	
Q20090510BBTMCL1	FDG313N	0/77		
Q20090510BBTMCL1	FDG313N		0/77	
Q20090510BCTMCL1	FDG313N	0/77		
Q20090510BCTMCL1	FDG313N		0/77	
Q20090510BDTMCL1	FDG313N	0/77		
Q20090510BDTMCL1	FDG313N		0/77	
Q20090510CATMCL1	FDG6323L	0/77		
Q20090510CATMCL1	FDG6323L		0/77	
Q20090510CBTMCL1	FDG6323L	0/77		
Q20090510CBTMCL1	FDG6323L		0/77	
Q20090510CCTMCL1	FDG6323L	0/77		
Q20090510CCTMCL1	FDG6323L		0/77	
Q20090510CDTMCL1	FDG6323L	0/77		
Q20090510CDTMCL1	FDG6323L		0/77	
Q20090510CETMCL1	FDG6323L	0/77		
Q20090510CETMCL1	FDG6323L		0/77	
Q20090510DATMCL1	NC7WZ17P6X	0/77		
Q20090510DATMCL1	NC7WZ17P6X		0/77	
Q20090510DBTMCL1	NC7WZ17P6X	0/77		
Q20090510DBTMCL1	NC7WZ17P6X		0/77	
Q20090510EATMCL1	FDG361N	0/77		
Q20090510EATMCL1	FDG361N		0/77	
Q20090510EBTMCL1	FDG361N	0/77		
Q20090510EBTMCL1	FDG361N		0/77	

Product Id Description : This final notification covers all Fairchild Semiconductor devices in SC70 package. For complete listing of the product covered in the PCN release, please refer to the affected FSID listing.

Affected FSIDs :

2N7002DW	BC847BS	BC847S
BC857S	FAN4174IP5X	FAN5358S710X
FAN5358S711X	FAN5358S712X	FAN5358S713X
FAN5358S715X	FAN5358S716X	FAN5358S718X
FAN5611S7X	FAN5612S7X	FAN5614S7X
FAN5640S7X	FAN5646S700X	FAN5646S701X
FDG1024NZ	FDG311N	FDG312P
FDG313N	FDG313N_D87Z	FDG315N
FDG316P	FDG327NZ	FDG327NZ_G
FDG327N	FDG328P	FDG330P
FDG332PZ	FDG332PZ_G	FDG410NZ
FDG6301N	FDG6301N_G	FDG6303N
FDG6303N_G	FDG6304P	FDG6304P_D87Z
FDG6304P_G	FDG6306P	FDG6306P_SBGX002
FDG6308P	FDG6308P_G	FDG6316P
FDG6316P_G	FDG6317NZ	FDG6318PZ
FDG6318P	FDG6320C	FDG6320C_G
FDG6321C	FDG6322C	FDG6323L
FDG6323L_NL	FDG6324L	FDG6324L_G
FDG6331L	FDG6331L_G	FDG6331L_NL

FDG6332C	FDG6332C_G	FDG6335N
FDG6335N_NBHX002	FDG6342L	FDG6
FDG8842CZ	FDG8850NZ	FDG901D
FFB2222A	FFB2227A	FFB2907A
FFB3904	FFB3904_G	FFB3904_NB23296
FFB3906	FFB3946	FFB5551
FFB5551_SBDB002A	FM20P5X	FMS6141S5X
FPF2000	FPF2000_F065	FPF2001
FPF2002	FPF2003	FPF2004
FPF2004_G	FPF2005	FPF2005_F065
FPF2005_G	FPF2005_SB82164	FPF2006
FPF2006_NBAA006	FPF2007	FPF2007_SB5S011
FPF2094	FPF2095	FSA1156P6X
FSA1156P6X_G	FSA1157P6X	FSA2156P6X
FSA3157P6X	FSA3157P6X_F40	FSA3157P6X_G
FSA4157AP6X	FSA4157P6X	FSA4157P6X_NF40
FSA4157P6X_SB82234	FSA4157P6	FSA4159P6X
FSA5157P6X	FSA66P5X	FSAU3157P6X
LMV321AP5X	LMV321AP5X_G	NC7S00P5X
NC7S00P5X_F40	NC7S00P5	NC7S02P5X
NC7S02P5	NC7S04P5X	NC7S04P5X_F065
NC7S04P5X_F40	NC7S04P5X_GF065	NC7S04P5X_G
NC7S04P5	NC7S08P5X	NC7S08P5X_F40
NC7S08P5	NC7S14P5X	NC7S14P5X_F40
NC7S14P5	NC7S32P5X	NC7S32P5X_G
NC7S32P5	NC7S86P5X	NC7S86P5X_G
NC7S86P5	NC7SB3157P6X	NC7SB3157P6X_F021
NC7SB3157P6X_F080	NC7SB3157P6X_F40	NC7SB3257P6X
NC7SB3257P6X_F40	NC7SBU3157P6X	NC7SP00P5X
NC7SP02P5X	NC7SP04P5X	NC7SP05P5X
NC7SP08P5X	NC7SP125P5X	NC7SP126P5X
NC7SP14P5X	NC7SP157P6X	NC7SP158P6X
NC7SP17P5X	NC7SP19P6X	NC7SP32P5X
NC7SP34P5X	NC7SP38P5X	NC7SP57P6X
NC7SP58P6X	NC7SP86P5X	NC7SPU04P5X
NC7ST00P5X	NC7ST00P5	NC7ST02P5X
NC7ST02P5	NC7ST04P5X	NC7ST04P5
NC7ST08P5X	NC7ST08P5X_F40	NC7ST08P5
NC7ST32P5X	NC7ST32P5	NC7ST86P5X
NC7ST86P5	NC7SU04P5X	NC7SU04P5X_F40
NC7SU04P5	NC7SV00P5X	NC7SV00P5X_G
NC7SV02P5X	NC7SV04P5X	NC7SV04P5X_G
NC7SV05P5X	NC7SV08P5X	NC7SV08P5X_F065
NC7SV08P5X_G	NC7SV11P6X	NC7SV125P5X
NC7SV126P5X	NC7SV14P5X	NC7SV157P6X
NC7SV158P6X	NC7SV17P5X	NC7SV17P5X_G
NC7SV19P6X	NC7SV32P5X	NC7SV32P5X_F065
NC7SV32P5X_G	NC7SV34P5X	NC7SV38P5X

NC7SV57P6X	NC7SV58P6X	NC7SV86P5X
NC7SVL04P5X	NC7SVL08P5X	NC7SVL32P5X
NC7SVU04P5X	NC7SZ00P5X	NC7SZ00P5X_F40
NC7SZ00P5	NC7SZ02P5X	NC7SZ02P5X_F40
NC7SZ02P5	NC7SZ04P5X	NC7SZ04P5X_F065
NC7SZ04P5X_F40	NC7SZ04P5	NC7SZ05P5X
NC7SZ05P5X_F40	NC7SZ05P5	NC7SZ08P5X
NC7SZ08P5X_F065	NC7SZ08P5X_F080	NC7SZ08P5X_F40
NC7SZ08P5X_G	NC7SZ08P5	NC7SZ10P6X
NC7SZ11P6X	NC7SZ125P5X	NC7SZ125P5X_F065
NC7SZ125P5X_F40	NC7SZ125P5X_G	NC7SZ125P5
NC7SZ126P5X	NC7SZ126P5X_F065	NC7SZ126P5X_F080
NC7SZ126P5X_F40	NC7SZ126P5X_G	NC7SZ126P5
NC7SZ14P5X	NC7SZ14P5X_F065	NC7SZ14P5X_F080
NC7SZ14P5X_F40	NC7SZ14P5	NC7SZ157P6X
NC7SZ157P6X_F065	NC7SZ157P6X_F40	NC7SZ175P6X
NC7SZ175P6X_F080	NC7SZ175P6X_G	NC7SZ175P6
NC7SZ18P6X	NC7SZ19P6X	NC7SZ19P6X_F065
NC7SZ19P6X_G	NC7SZ19P6	NC7SZ27P6X
NC7SZ32P5X	NC7SZ32P5X_F065	NC7SZ32P5X_F40
NC7SZ32P5X_G	NC7SZ32P5	NC7SZ332P6X
NC7SZ332P6X_F40	NC7SZ373P6X	NC7SZ373P6
NC7SZ374P6X	NC7SZ374P6	NC7SZ384P5X
NC7SZ386P6X	NC7SZ38P5X	NC7SZ38P5
NC7SZ57P6X	NC7SZ57P6X_F065	NC7SZ58P6X
NC7SZ58P6X_F065	NC7SZ66P5X	NC7SZ66P5X_F40
NC7SZ66P5X_G	NC7SZ66P5X_NF40	NC7SZ86P5X
NC7SZ86P5X_F40	NC7SZ86P5	NC7SZD384P5X
NC7SZD384P5X_NF40	NC7SZU04P5X	NC7SZU04P5X_F40
NC7SZU04P5	NC7WP14P6X	NC7WV04P6X
NC7WV07P6X	NC7WV14P6X	NC7WV16P6X
NC7WV16P6X_G	NC7WV17P6X	NC7WZ04P6X
NC7WZ04P6X_F065	NC7WZ04P6X_F080	NC7WZ04P6X_F40
NC7WZ04P6X_G	NC7WZ04P6	NC7WZ07P6X
NC7WZ07P6X_F065	NC7WZ07P6X_F080	NC7WZ07P6X_F40
NC7WZ07P6	NC7WZ14EP6X	NC7WZ14P6X
NC7WZ14P6X_F065	NC7WZ14P6X_F40	NC7WZ14P6
NC7WZ16P6X	NC7WZ16P6X_F065	NC7WZ16P6X_F40
NC7WZ16P6	NC7WZ17P6X	NC7WZ17P6X_F065
NC7WZ17P6X_F40	NC7WZ17P6X_G	NC7WZ17P6
NC7WZU04P6X	NC7WZU04P6X_F065	NC7WZU04P6